

Search Notes

Application/Control No.

10/619,111

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

SHU ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
216	41	7/5/2005	BT
216	42	7/5/2005	BT
216	43	7/5/2005	BT
216	48	7/5/2005	BT
216	75	7/5/2005	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
216	41	7/5/2005	BT
216	42	7/5/2005	BT
216	43	7/5/2005	BT
216/48 216/75		7/5/2005	BT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update search using US-PGPUB, USPAT, EPO, JPO, DERWENT, IBM_TBD databases	7/5/2005	BT